

**Description:**

Computer-controlled instrument, for reliable and accurate measurement of unevenness and imperfection of sliver, roving, and yarn with fault analysis software

Features

- Advanced and reliable capacitance-based sensor
- Measures:
 - U%, CV
 - In 4 levels: Thick, Thin, and Nep
 - Relative count
 - DR %
 - Index, etc.
- Measurement speeds (selectable):
 - 25 m/min
 - 50 m/min
 - 100 m/min
 - 200 m/min
 - 400 m/min (or in yards/min)
- Four measuring slots to accommodate material from 0.007 nec to 150 nec
- Auto-positioning of measuring slot
- Fault analyzing software to locate fault
- Results will be stored in the computer for future reference

Note: Specifications are subject to change, Photos shown above are Indicative, Actual Product can Vary.



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